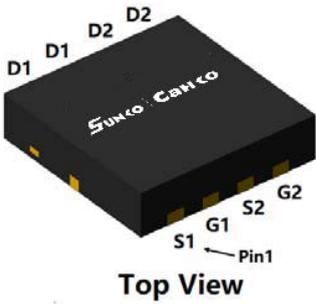
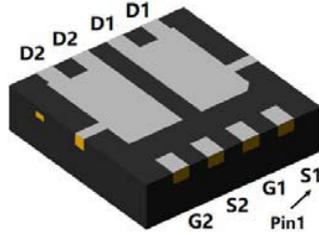


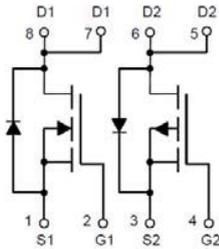
P-Channel Enhancement Mode Field Effect Transistor



Top View



Bottom View



DFN3333-8L

Product Summary

- V_{DS} -20V
- I_D -30A
- $R_{DS(ON)}$ (at $V_{GS} = -4.5V$) < 19mohm
- $R_{DS(ON)}$ (at $V_{GS} = -2.5V$) < 22mohm
- $R_{DS(ON)}$ (at $V_{GS} = -1.8V$) < 30mohm

General Description

- Trench Power MV MOSFET technology
- High density cell design for Low $R_{DS(ON)}$
- High Speed switching
- Moisture Sensitivity Level 3
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

Applications

- Battery protection
- Load switch
- Power management

■ Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise noted)

Parameter		Symbol	Maximum	Unit
Drain-source Voltage		V_{DS}	-20	V
Gate-source Voltage		V_{GS}	± 10	V
Drain Current	$T_C=25^\circ C$ @ Steady State	I_D	-30	A
	$T_C=100^\circ C$ @ Steady State		-19	
	$T_A=25^\circ C$ @ Steady State		-10	
	$T_A=100^\circ C$ @ Steady State		-6	
Pulsed Drain Current ^A		I_{DM}	-55	A
Single Pulse Avalanche Energy		E_{AS}	31	mJ
Total Power Dissipation ^B	$T_C=25^\circ C$ @ Steady State	P_D	21	W
	$T_C=100^\circ C$ @ Steady State		8.4	
	$T_A=25^\circ C$ @ Steady State		3	
	$T_A=100^\circ C$ @ Steady State		1.2	
Thermal Resistance Junction-to-Ambient @ Steady State ^C		$R_{\theta JA}$	42	$^\circ C/W$
Thermal Resistance Junction-to-Case @ Steady State		$R_{\theta JC}$	5.9	$^\circ C/W$
Junction and Storage Temperature Range		T_J, T_{STG}	-55~+150	$^\circ C$

■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
SCQD30P02A	F1	Q30P02	5000	10000	100000	13" reel

■ Electrical Characteristics (T_J=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =-250μA	-20			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-20V, V _{GS} =0V, T _C =25°C			-1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} = ±10V, V _{DS} =0V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D =-250μA	-0.4	-0.62	-1.0	V
Static Drain-Source On-Resistance	R _{DS(ON)}	V _{GS} = -4.5V, I _D =-15A		11	19	mΩ
		V _{GS} = -2.5V, I _D =-8A		14	22	
		V _{GS} = -1.8V, I _D =-6.0A		20	30	
Diode Forward Voltage	V _{SD}	I _S =-30A, V _{GS} =0V		-0.8	-1.2	V
Dynamic Parameters						
Input Capacitance	C _{iss}	V _{DS} =-10V, V _{GS} =0V, f=1MHZ		2992		pF
Output Capacitance	C _{oss}			330		
Reverse Transfer Capacitance	C _{rss}			272		
Switching Parameters						
Total Gate Charge	Q _g	V _{GS} =-10V, V _{DS} =-15V, I _D =-9.1A		72.8		nC
Gate Source Charge	Q _{gs}			6.6		
Gate Drain Charge	Q _{gd}			10.1		
Reverse Recovery Charge	Q _{rr}	I _F =-6A, di/dt=100A/us		34		
Reverse Recovery Time	t _{rr}			67		
Turn-on Delay Time	t _{D(on)}	V _{GS} =-10V, V _{DS} =-15V, I _D =-6A, R _{GEN} =2.5Ω		7		ns
Turn-on Rise Time	t _r			33		
Turn-off Delay Time	t _{D(off)}			130		
Turn-off Fall Time	t _f			132		

A. Pulse Test: Pulse Width ≤ 300us, Duty cycle ≤ 2%.

B. P_q is based on max. junction temperature, using junction-case and junction-ambient thermal resistance.

C. R_{θJA} is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θJC} is guaranteed by design, while R_{θJA} is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

■ Typical Performance Characteristics

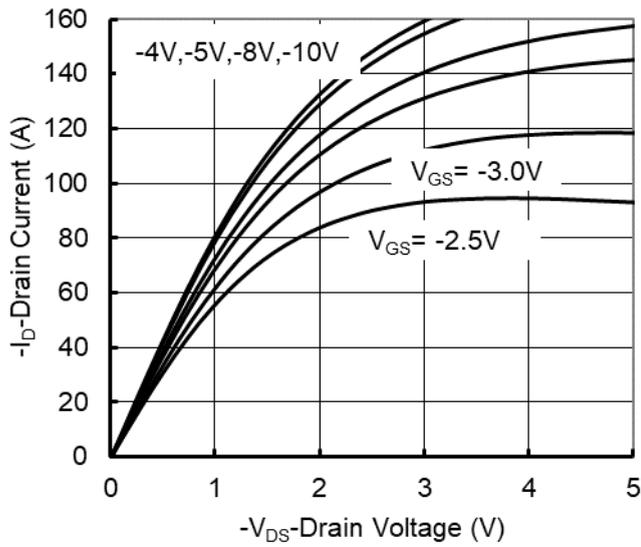


Figure 1. Output Characteristics

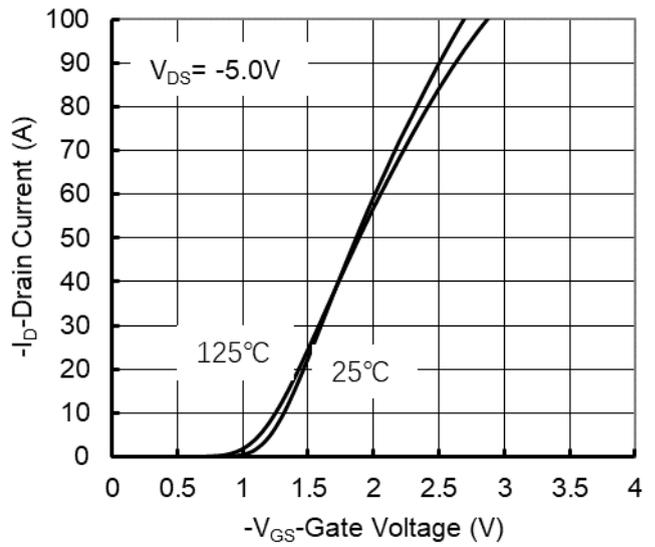


Figure 2. Transfer Characteristics

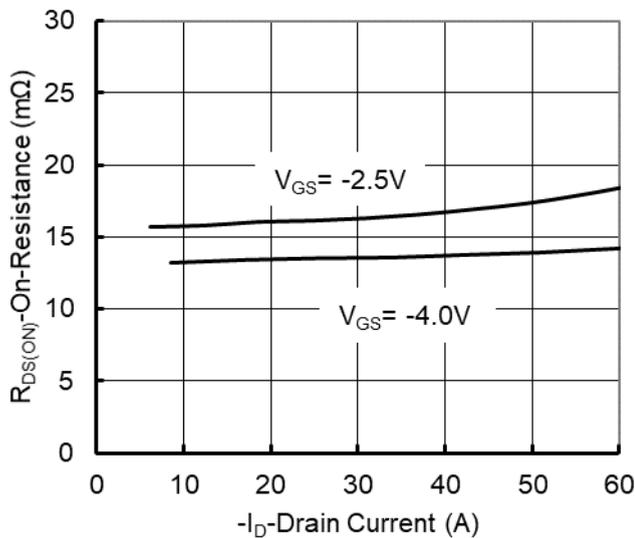


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

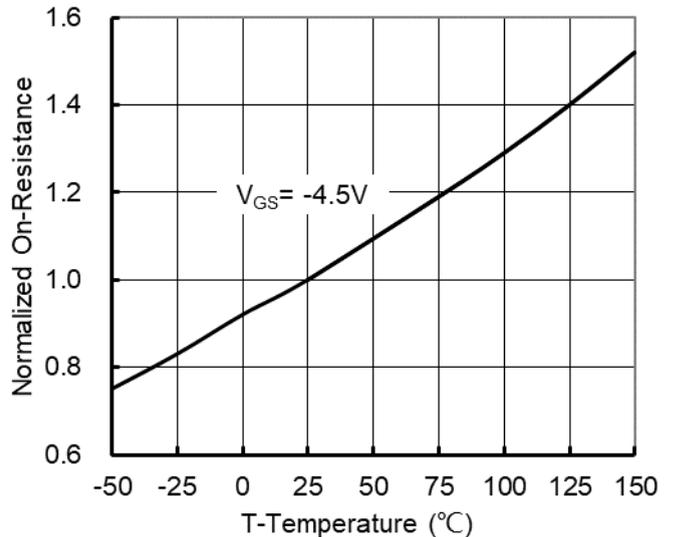


Figure 4. On-Resistance vs. Junction Temperature

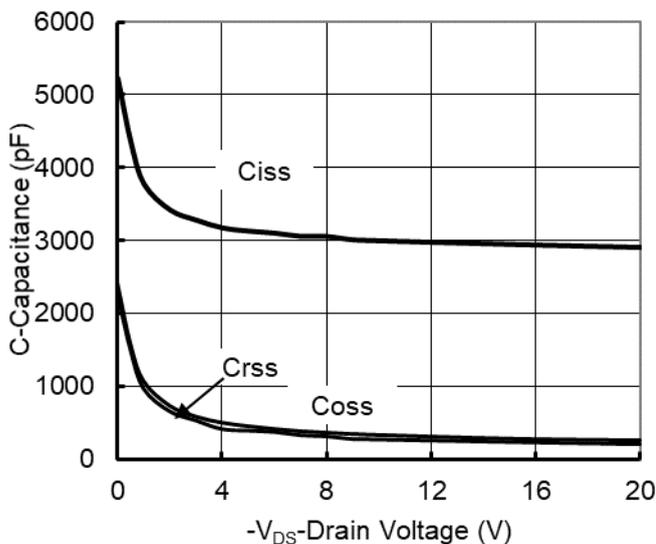


Figure 5. Capacitance Characteristics

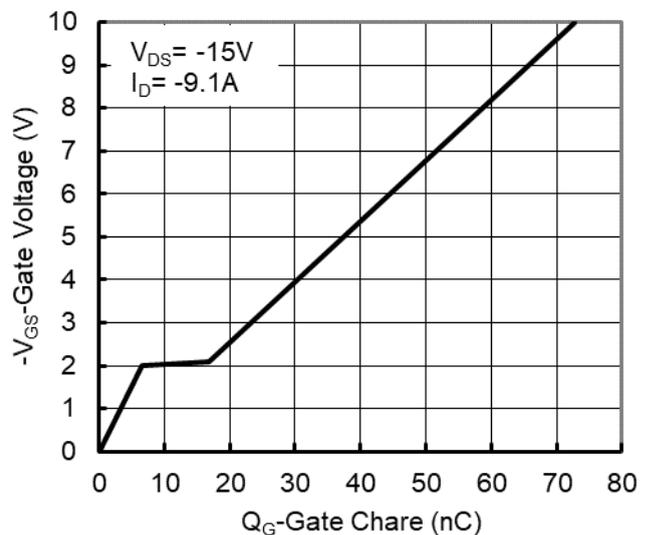


Figure 6. Gate Charge

SCQD30P02A

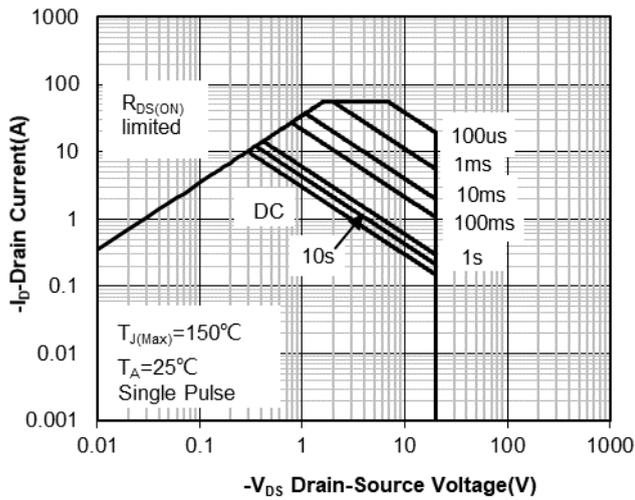


Figure 7. Safe Operation Area

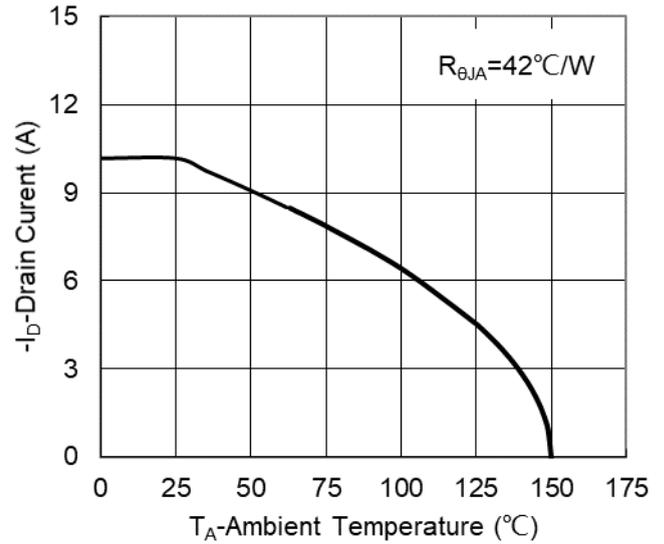


Figure 8. Maximum Continuous Drain Current vs Ambient Temperature

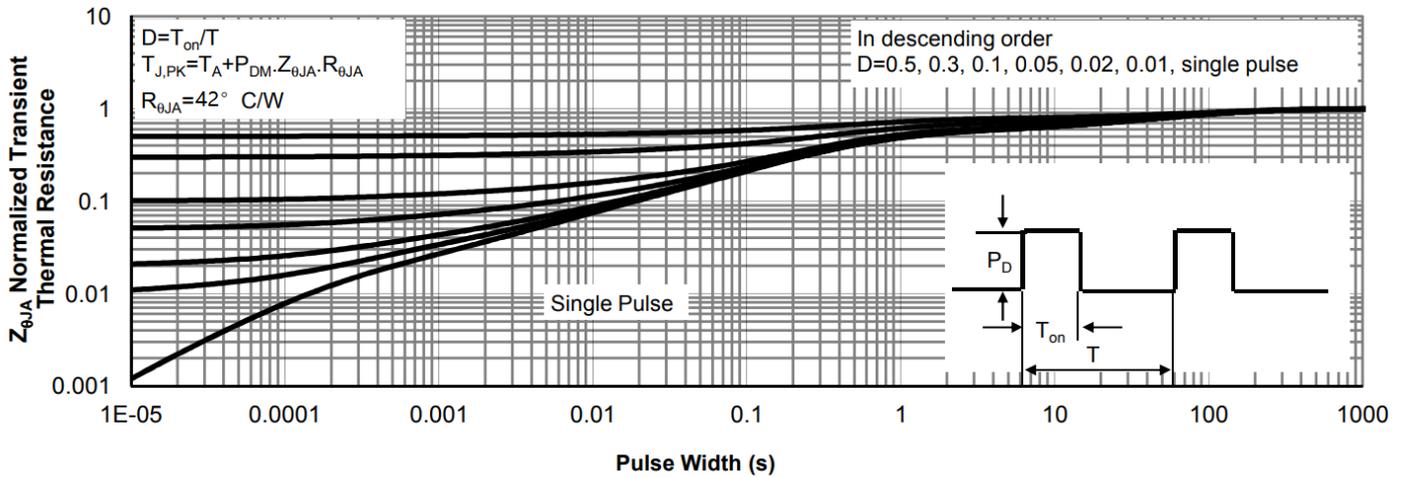
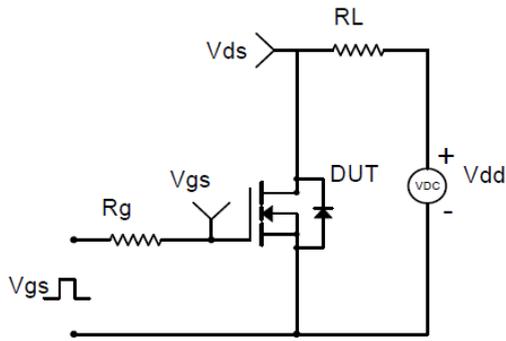
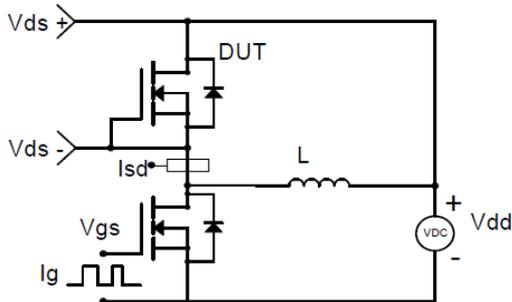


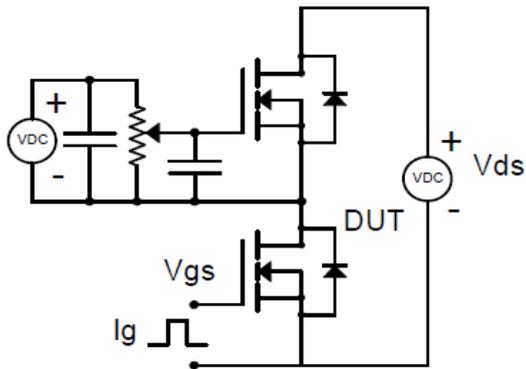
Figure 9. Normalized Maximum Transient Thermal Impedance



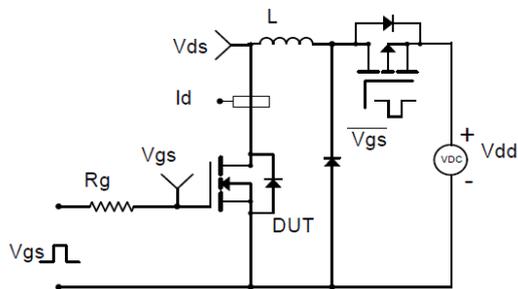
Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

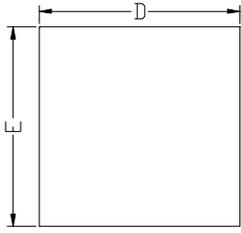


Gate Charge Test Circuit & Waveform

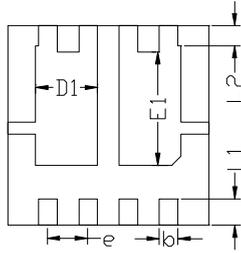


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

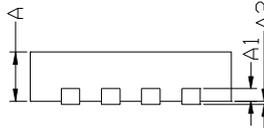
■ DFN3333-8L Package information



Top View
正面视图

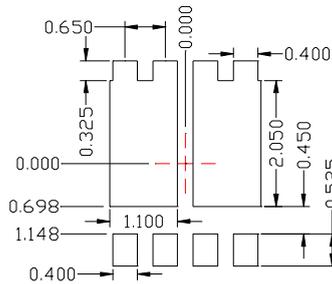


Bottom View
背面视图



Side View
侧面视图

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	3.15	3.25	3.35
E	3.15	3.25	3.35
A	0.70	0.80	0.90
A1	0.20 BSC		
A2			0.10
D1	0.90	1.00	1.10
E1	1.75	1.85	1.95
L1	0.325	0.425	0.525
L2	0.325 BSC		
b	0.20	0.30	0.40
e	0.65 BSC		



Suggested Solder Pad Layout
Top View

Note:

1. Controlling dimension: in millimeters.
2. General tolerance: +/-0.10mm.
3. The pad layout is for reference purposes only.

Disclaimer

The information presented in this document is for reference only. Shanghai Sunco Electronics Co., Ltd reserves the right to make changes without notice for the specification of the products displayed herein to improve reliability, function or design or otherwise.

The product listed herein is designed to be used with ordinary electronic equipment or devices, and not designed to be used with equipment or devices which require high level of reliability and the malfunction of which would directly endanger human life (such as medical instruments, transportation equipment, aerospace machinery, nuclear-reactor controllers, fuel controllers and other safety devices), Russiansunco or anyone on its behalf, assumes no responsibility or liability for any damages resulting from such improper use of sale.

This publication supersedes & replaces all information previously supplied. For additional information, please visit our website [http:// www.russiansunco.com](http://www.russiansunco.com) or consult your nearest Russiansunco's sales office for further assistance.